

SLOVENSKI STANDARD SIST EN 62321-3-1:2014

01-junij-2014

Nadomešča:

SIST EN 62321:2009

Določevanje posameznih snovi v elektrotehničnih izdelkih - 3-1. del: Presejanje elektrotehničnih izdelkov glede svinca, živega srebra, kadmija, celotnega kroma in celotnega broma z rentgensko fluorescenčno spektrometrijo (IEC 62321-3-1:2013)

Determination of certain substances in electrotechnical products - Part 3-1: Screening test methods - Screening of electrotechnical products for lead, mercury, cadmium, total chromium and total bromine using X-ray fluorescence spectrometry

Verfahren zur Bestimmung von bestimmten Substanzen in Produkten der Elektrotechnik - Teil 3-1: Ermittlung von Blei (Pb), Quecksilber (Hg), Cadmium (Cd), Gesamtchrom (Cr) und Brom (Br) durch Röntgenfluoreszenz-Spektrometrie in elektrotechnischen Produkten https://standards.iteh.avcatalog/standards/sist/9101d146-90/c-4a12-9965-d0d2b345e45c/sist-en-62321-3-1-2014

Détermination de certaines substances dans les produits électrotechniques -- Partie 3-1: Détection du plomb, du mercure, du cadmium, du chrome total et du brome total dans les produits électrotechniques par spectrométrie par fluorescence X

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general

31.020 Elektronske komponente na Ele

Electronic components in

splošno

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EUROPEAN STANDARD

EN 62321-3-1

NORME FUROPÉENNE **EUROPÄISCHE NORM**

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English version

Determination of certain substances in electrotechnical products -Part 3-1: Screening -

Lead, mercury, cadmium, total chromium and total bromine by X-ray fluorescence spectrometry

(IEC 62321-3-1:2013)

Détermination de certaines substances dans les produits électrotechniques -Partie 3-1: Méthodes d'essai -Plomb, du mercure, du cadmium, du chrome total et du brome total par la spectrométrie par fluorescence X DARD PGesamtchrom und Gesamtbrom durch (CEI 62321-3-1:2013)

Verfahren zur Bestimmung von bestimmten Substanzen in Produkten der Elektrotechnik -Teil 3-1: Screening -Blei, Quecksilber, Cadmium, (standards.itelRöntgenfluoreszenz-Spektrometrie (IEC 62321-3-1:2013)

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European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B - 1000 Brussels

Foreword

The text of document 111/298/FDIS, future edition 1 of IEC 62321-3-1, prepared by IEC/TC 111 "Environmental standardization for electrical and electronic products and systems" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62321-3-1:2014.

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SIST EN 62321-3-1:2014

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 62321-1	-	Determination of certain substances in electrotechnical products - Part 1: Introduction and overview	EN 62321-1	-
IEC 62321-2	-	Determination of certain substances in electrotechnical products - Part 2: Disassembly, disjunction and mechanical sample preparation	EN 62321-2	-
ISO/IEC Guide 98-1	iT	Uncertainty of measurement - Part 1: Introduction to the expression of IF uncertainty in measurement (standards.iteh.ai)	W	-

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INTERNATIONAL STANDARD

NORME INTERNATIONALE



Determination of certain substances in electrotechnical products –
Part 3-1: Screening – Lead, mercury, cadmium, total chromium and total bromine by X-ray fluorescence spectrometry

SIST EN 62321-3-1:2014

Détermination de certaines substances dans les produits électrotechniques – Partie 3-1: Méthodes d'essai Plomb, du mercure, du cadmium, du chrome total et du brome total par la spectrométrie par fluorescence X

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

DETERMINATION OF CERTAIN SUBSTANCES IN ELECTROTECHNICAL PRODUCTS –

Part 3-1: Screening – Lead, mercury, cadmium, total chromium and total bromine by X-ray fluorescence spectrometry

FOREWORD

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International Standard IEC 62321-3-1 has been prepared by IEC technical committee 111: Environmental standardization for electrical and electronic products and systems.

The first edition of IEC 62321:2008 was a 'stand alone' standard that included an introduction, an overview of test methods, a mechanical sample preparation as well as various test method clauses.

This first edition of IEC 62321-3-1 is a partial replacement of IEC 62321:2008, forming a structural revision and generally replacing Clauses 6 and Annex D.

Future parts in the IEC 62321 series will gradually replace the corresponding clauses in IEC 62321:2008. Until such time as all parts are published, however, IEC 62321:2008 remains valid for those clauses not yet re-published as a separate part.

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The text of this standard is based on the following documents:

FDIS	Report on voting	
111/298/FDIS	111/308/RVD	

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62321 series can be found on the IEC website under the general title: Determination of certain substances in electrotechnical products

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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INTRODUCTION

The widespread use of electrotechnical products has drawn increased attention to their impact on the environment. In many countries this has resulted in the adaptation of regulations affecting wastes, substances and energy use of electrotechnical products.

The use of certain substances (e.g. lead (Pb), cadmium (Cd) and polybrominated diphenyl ethers (PBDEs)) in electrotechnical products, is a source of concern in current and proposed regional legislation.

The purpose of the IEC 62321 series is therefore to provide test methods that will allow the electrotechnical industry to determine the levels of certain substances of concern in electrotechnical products on a consistent global basis.

WARNING – Persons using this International Standard should be familiar with normal laboratory practice. This standard does not purport to address all of the safety problems, if any, associated with its use. It is the responsibility of the user to establish appropriate safety and health practices and to ensure compliance with any national regulatory conditions.

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